

CIL
EMU CRITICAL ITEMS LIST

12/24/91 SUPERSEDES DB/31/90

MMAL(ET)

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NAME P/N QTY	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE
CAUTION AND WARNING SYSTEM, ITEM 15B ----- SU785970-15 (1)	2/2	1501MIB; BITE circuit fails (CMR). CAUSE: Electronic component failure.	END ITEM: BITE Indicator on DCM is continuously on. OPE INTERFACE: Indication of a CMS failure but unaccompanied by a warning tone or display backlighting. MISSION: Terminate EMU when BITE indicator is noticed during periodic status checks, or when tone sounds. CREW/VEHICLE: None.	A. Design - Established reliability capacitors and resistors are qualified to applicable military standards and thermal shocked per Condition B Test Method 107 of MIL-STD-202. Microcircuits are qualified to the requirements of MIL-M-38510 and receive the burn-in of Class B parts per Method 5884 of MIL-STD-883. Transistors, diodes are qualified to the requirements of MIL-S-19500 and receive the burn-in of JANFNU level parts per the applicable Methods, 1835, 1939, 1040 of MIL-STD-750. The electronic components are operating within the power dissipating requirements of SVHS7004. The printed (PC) boards are fiberglass/epoxy per MIL-P-13949 type 0F and manufactured in accordance with GR-P-0006. Parts mounting and soldering is per NSFC-STD-136 and MMS300.4 (3K-1). The CMS is a mother/daughter board assembly. The daughter boards are held in place by metal card guides which also provide thermal transfer from the boards to the CMS case. The top cover of the CMS exerts a downward force on the daughter boards to keep them properly seated in the mother board connectors. Flex Tape (Kapton Insulated, flexible flat conductor) instead of conventional teflon coated wires is used to provide connections between the mother board and the external connectors. This prevents pinching of the conductor during item assembly. The PC board assemblies are conformal coated per MIL-A 66146 (COW Corning RTV 316B) for environmental and humidity protection. Electrical connectors are environmentally sealed to prevent damage due to contamination and humidity. B. Test - Component Acceptance Test - Full functioning of the CMS is verified during Item RIP tests included continuity, logic flow, x-state sequencing, fault simulation, verification of status and fault messages, warning and alert tones activation, and BITE activation. These tests are conducted upon completion of random vibration testing (6.1 gms). PDA Test - The above electrical tests are repeated during PLSS PDA to verify CMS operation. The CMS is also operational during

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	2/2	15BFH10r		<p>other PLSS PDA electrical tests such as sensor accuracy checks, Item 123 Fan Operation, Item 174 BYDS checkout, and Solenoid Valve Actuation.</p> <p>Certification Test - The item completed the 15 year structural vibration and shock certification tests during 90/83. EC's 42806-244 (add Jumper wires, add diode CR221, change resistor R301), 42806-345-3 (eliminate interferences with PLSS), 42806-718 (overstressed resistor R303 due to an improper interface circuit in the delta toggle GFE, software change, diode VR201 rewiring) 42806-942 and 42806-042-1 (transistor Q207 lead stress relief) have been incorporated and certified by similarity or analysis since this configuration was tested.</p> <p>Checkout Test - Proper operation of the CMS is verified during electrical PIA tests per FEMU-B-001 during such tests as Transducer and DCN Gauge Calibration Check (RPIA). A full CMS Logic Test is performed a minimum of one every two years per FEMU-B-001, CMS Logic Flow test.</p> <p>C. Inspection - Each circuit board, the flex tape, and connectors are inspected for damage and contamination prior to being placed into finished stores. The CMS assembly is inspected internally and externally for damage and contamination during item assembly and externally during ATP. All soldering is inspected by N9 QA and NCAS QA per WBS300.4 (JA-1).</p> <p>D. Failure History - J-EMU-150-AB01 (7-16-85) During PIA testing, several failures occurred: BITE light did not come on after power inchover as required, CMS failed the entire Logic Flow Test, and BITE failed the Tone Test. The BITE light failure was due to a short circuit in the flex tape between battery power discrete and BITE light control line. The Logic Flow and Tone Test failures were due to a faulty EPROM in the CMS. Both the flex tape assembly and the faulty EPROM were replaced. Additional tests were added to the CMS IPR and PDA via EC 42806-896.</p>

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	2/2	ISOPW10;		<p>E. Ground Turnaround - Tested per FEMU-A-001, bite light verification.</p> <p>F. Operational Use - Crew Response Pre/Post EVA: Verify status list operational. EMU go for EVA. Consider EMU 3 if available. EVA: Verify status list operational. Continue EVA. Rely on tone for future bite failure warning. Training: Standard training covers this failure mode. Operational Considerations: Flight rules define EMU go/no-go criteria related to CMS. EVA checklist procedures verify hardware integrity and systems operational status prior to EVA. Real Time Data System allows ground monitoring of EMU systems.</p>